

Search Notes

Application/Control No.

10/786,072

Examiner

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Applicant(s)/Patent under
Reexamination

ISHII ET AL.

Art Unit

2163

SEARCHED

Class	Subclass	Date	Examiner
709	229	11/18/2005	PAD
709	225	11/18/2005	PAD
709	218	11/18/2005	PAD
709	104	11/18/2005	PAD
455	410	11/18/2005	PAD

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	11/18/2005	PAD
PLUS	11/18/2005	PAD
IEEE DATABASE	11/19/2005	PAD